

Untestable fault identification in sequential circuits using model-checking

Raik, Jaan; Fujiwara, Hideo; **Ubar, Raimund-Johannes**; **Krivenko, Anna** Proceedings of the 17th Asian Test Symposium ATS 2008 : November 24-27, 2008, Sapporo, Japan 2008 / p. 21-26 : ill <http://dx.doi.org/10.1109/ATS.2008.22>